

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/523,193	SHEN ET AL.	
Examiner		Art Unit		Page 1 of 2
David Garcia Cervetti		2136		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2001/0033660 A1	10-2001	Maeda, Mitsuru	380/232
*	B	US-2001/0041061 A1	11-2001	Nakagawa, Toshiyuki	386/111
*	C	US-2002/0035544 A1	03-2002	Wakao et al.	705/51
*	D	US-2002/0156712 A1	10-2002	Rambhia, Avni Harilal	705/36
*	E	US-2003/0016744 A1	01-2003	Nakagawa, Toshiyuki	375/240.01
*	F	US-2003/0028397 A1	02-2003	Tagashira et al.	705/1
*	G	US-2003/0118188 A1	06-2003	Collier et al.	380/277
*	H	US-2003/0163430 A1	08-2003	Takaku, Masahiko	705/52
*	I	US-6,643,330 B1	11-2003	Nakagawa et al.	375/240.28
*	J	US-2003/0229900 A1	12-2003	Reisman, Richard	725/87
*	K	US-2004/0031058 A1	02-2004	Reisman, Richard	725/112
*	L	US-2005/0044016 A1	02-2005	Irwin et al.	705/030
*	M	US-6,891,953 B1	05-2005	DeMello et al.	380/277

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

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	U	
	V	
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	X	

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Notice of References Cited		Application/Control No. 10/523,193	Applicant(s)/Patent Under Reexamination SHEN ET AL.	
		Examiner David Garcia Cervetti	Art Unit 2136	Page 2 of 2

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,931,541 B1	08-2005	Nakagawa, Toshiyuki	713/193
*	B	US-6,970,849 B1	11-2005	DeMello et al.	705/52
*	C	US-6,981,262 B1	12-2005	DeMello et al.	719/310
*	D	US-7,099,491 B2	08-2006	Takaku, Masahiko	382/100
*	E	US-7,099,473 B2	08-2006	Maeda, Mitsuru	380/239
*	F	US-7,158,953 B1	01-2007	DeMello et al.	705/51
*	G	US-7,231,043 B2	06-2007	Maeda, Mitsuru	380/202
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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